Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-1776

SERIAL NO. 09/943,180

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PANL	AA	3,627,598	12/71	McDonald et al.						
PANC	AB	4,254,161	03/81	Kemlage						
RML	AC	4,262,631	04/81	Kubacki		_				
UNI	AD	4,435,447	3/84	lto et al.						
RM	AE	4,882,649	11/89	Chen et al.			/			
PUR	AF	4,891,684	01/90	Nishioka et al.						
PUR	AG	4,980,307	12/90	Ito et al.		/	/			
RWR	АН	4,996,081	02/91	Ellul et al.		/				
RUR	Al	5,026,574	06/91	Economu et al.		_				
PMR	AJ	5,032,545	07/91	Doan et al.		/	/			
run	AK	5,051,794	09/91	Mori		/	/			
pur	AL	5,142,438	08/92	Reinberg et al.						
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	AS	Wolf, Stanley, "	Silicon Processing	for the VLSI Era", vol. 2, pp. 2	212-213, 1990.					
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RAME	AA	5,227,651	07/93	Kim et	t al.			/		
rur	AB	5,237,188	08/93	Iwai e	t al.			/		
RNP	AC	5,254,489	10/93	Nakata			/	/		
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RMR	AE	5,324,679	06/94	Kim et	tal.			/		
nur	AF	5,330,936	07/94	Ishitan	i		/	/		
rur	AG	5,350,707	09/94	Ko et	al.		/	/		
pup	АН	5,376,593	12/94	Sandhu	et al.		/	/		
rur	AI	5,378,645	01/95	Inoue	et al.		/			
RMV-	AJ	5,382,533	01/95	Aḥmad	l et al.					
ana	AK	5,393,702	02/95	Yang e	et al.					
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-1776

SERIAL NO. 09/943,180

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

FILING DATE August 29, 2001

APPLICANT Moore et al.

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Examiner Initial CUNC CUNC	AA AB AC AD AE AF AG AH AI	Document Number 5,436,481 5,445,999 5,459,105 5,464,792 5,498,890 5,504,029 5,504,029 5,508,542 5,518,946 5,523,596 5,596,218	Date 07/95 08/95 10/95 11/95 03/96 04/96 05/96 06/96	Name Egawa et al. Thakur et al. Matsuura Tseng et al. Kim et al. Murata et al. Geiss et al.	Class	Subclass	Filing If Appr	
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RUR	AK	5,612,558	11/95	Harshfield				
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PANR	AA	5,620,908	04/97	Inoh et al.		/	/		
RAR	AB	5,663,036	05/97	Seebauer et al.		/			
RAIR	AC	5,663,077	09/97	Adachi et al.		/	/		
run	AD	5,674,788	10/97	Wristers et al.		/			
run	AE	5,716,864	02/98	Abe					
run	AF	5,719,083	06/95	Komatsu	****	/			
PEMP	AG	5,731,235	03/98	Srinvasan et al.			/		
pur	АН	5,760,475	06/98	Cronin			/		
runc	Al	5,834,372	11/98	Lee		/	/		
PM	ΑJ	5,844,771	12/98	Graettinger et al.		/	/		
RANC	AK	5,821,142	10/98	Sung et al.		/	/		
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PARL	AA	5,939,750	08/99	Early		/	/		
PWR	AB	5,960,302	09/99	Ma et al.		/			
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RNP	AD	5,994,749	11/99	Oda					
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RNP	AG	6,093,661	07/00	Trivedi et al.	·				
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RMR	AI	09/633,556		Sandhu et al.	14.			08/07/2000	
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PUR	AA	5,330,920	07/94	Soleimani et al.				
PAR	AB	5,633,036	05/97	Seebauer et al.		(-	
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PAIR	AE	6,091,109	07/00	Hasegawa				
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RNR	AG	6,110,842	08/00	Okuno et al.		-		.i .
RMZ	AH	6,114,203	09/00	Ghidini et al.				
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RUR	AJ	6,197,701	03/01	Shue et al.				
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RNR	AB	5,960,289	09/99	Tsui et al.						
RNR	AC	5,998,253	12/99	Loh et al.						
PUR	AD	6,033,998	03/00	Aronowitz et al.			_			
PUR	AE	6,057,220	05/00	Ajmera et al.						
RNR	AF	6,087,229	07/00	Aronowitz et al.			_			
RNR	AG	6,136,636	10/00	Wu			_			
PNR	АН	6,225,167	05/01	Yu et al.		_	_			
PUR	Al	6,228,701 B1	05/01	Dehm et al.						
RMZ	AJ	6,255,703 B1	07/01	Hause et al						
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Par	АВ	5,164	,331	11/1992	Lin et al.					
Par	AC	5,318	,924	06/1994	Lin et al.					
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PWR	AG	5,837	,592	11/1998	Chang et al.					
Par	АН	5,837	,598	11/1998	Aronowitz et al.					
PNR	AI	5,885	,877	03/1999	Gardner et al.		_			
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an	AA	6,146,948	11/2000	Wu et al.		_			
SNS	AB	6,184,110 B1	02/2001	Ono et al.					
PANR	AC	6,201,303 B1	03/2001	Ngo et al.					
ROVE	AD	6,207,586	03/2001	Ma et al.			_		
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PNR	AF	6,323,114 B1	11/2001	Hattangady et al.				ļ	
RMR	AG	6,331,492 B2	12/2001	Misium et al.					
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